

REMARKS

1. Further prosecution of the above-identified application are respectfully requested in view of the discussion that follows.

Claims 25-42 are now pending in this application. Claims 25-42 were allowed on 11/3/05. The Request for Continued Examination was filed to allow consideration of U.S. Pat. Publ. No. US 2002/0181526 to Gao.

Gao shows a number of contact/protection pads 14, 18 for protecting the surface of a diode chip 10. FIG. 4 of Gao shows contact/protection pads 14, 18 abutting the laser ridge 16.

Gao differs from the claimed invention in that the claims are limited to pads "only in the inactive areas" on the surface of the wafer. Not only do the contact protection pads 14, 18 of Gao overlap the active areas of the diode 10 as shown in FIG. 4, but "The contact/protection pad 14 . . . provides a contact point for the p-side of the p-n junction of the laser diode 10" (Gao, par. [0030]). Since the contact/protection pad 14 provides a contact point for the p-n junction, the Gao contact/protection pads 14 clearly overlap an active region of the diode 10.

Since the Gao contact/protection pads 14, 18 overlap the active regions of the diode 10, Gao does not teach or suggest "a plurality of pads around a periphery of at least some semiconductor chips . . . only in said inactive areas". Since Gao does not meet at least this claim limitation, the claims are believed to be allowable.

2. Allowance of claims 24-42, as now presented, is

believed to be in order and such action is earnestly solicited. Should the Examiner be of the opinion that a telephone conference would expedite prosecution of the subject application, he is respectfully requested to telephone applicant's undersigned attorney.

Respectfully submitted,
WELSH & KATZ, LTD.

By 

Jon P. Christensen
Registration No. 34,137

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WELSH & KATZ, LTD.
120 South Riverside Plaza
22nd Floor
Chicago, Illinois 60606
(312) 655-1500